# **BLF6G20-230PRN**

### **Power LDMOS transistor**

Rev. 01 — 2 December 2008

**Objective data sheet** 

### 1. Product profile

### 1.1 General description

230 W LDMOS power transistor for base station applications at frequencies from 1800 MHz to 2000 MHz.

Table 1. Typical performance

RF performance at  $T_{case}$  = 25 °C in a common source class-AB production test circuit.

Mode of operation	f	$V_{DS}$	$P_{L(AV)}$	Gp	$\eta_{D}$	ACPR
	(MHz)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	1805 to 1880	28	50	16.5	29.5	-35 <mark>[1]</mark>

<sup>[1]</sup> Test signal: 3GPP; test model 1; 64 DPCH; PAR = 7.5 dB at 0.01 % probability on CCDF per carrier; carrier spacing 5 MHz.

#### **CAUTION**



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

### 1.2 Features

- Typical 2-carrier W-CDMA performance at frequencies of 1805 MHz and 1880 MHz, a supply voltage of 28 V and an I<sub>Dq</sub> of 2000 mA:
  - ◆ Average output power = 50 W
  - Power gain = 16.5 dB (typ)
  - ◆ Efficiency = 29.5 %
  - ◆ ACPR = -35 dBc
- Easy power control
- Integrated ESD protection
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (1800 MHz to 2000 MHz)
- Internally matched for ease of use
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)



### 1.3 Applications

■ RF power amplifiers for W-CDMA base stations and multi carrier applications in the 1800 MHz to 2000 MHz frequency range

# 2. Pinning information

Table 2. Pinning

Pin	Description	Simplified outline	Graphic symbol
1	drain1		
2	drain2	1 2	
3	gate1	<b>≥</b>	3
4	gate2	3 4	5
5	source	<u>[1]</u>	4—
			l 2 sym117

<sup>[1]</sup> Connected to flange

# 3. Ordering information

Table 3. Ordering information

Type number	Package				
	Na me	Description	Version		
BLF6G20-230PRN	-	flanged balanced LDMOST ceramic package; 2 mounting holes; 4 leads	SOT539A		

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage		-	65	V
$V_{GS}$	gate-source voltage		-0.5	+13	V
T <sub>stg</sub>	storage temperature		-65	+150	°C
T <sub>case</sub>	case temperature		-	150	°C
T <sub>j</sub>	junction temperature		-	225	°C

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### 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{\text{th(j-case)}}$	thermal resistance from junction to case	$T_{case} = 80  ^{\circ}C;$ $P_{L(AV)} = 50  W$	0.38	K/W

### 6. Characteristics

#### Table 6. Characteristics

 $T_i = 25 \,^{\circ}C$  per section; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.5 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_{D} = 144 \text{ mA}$	1.575	1.9	2.3	V
$V_{GSq}$	gate-source quiescent voltage	$V_{DS} = 32 \text{ V}; I_D = 800 \text{ mA}$	1.725	2.1	2.45	V
I <sub>DSS</sub> drain leakage current		$V_{GS} = 0 V$				
		$V_{DS} = 28 \text{ V}$	-	-	3	μΑ
		$V_{DS} = 60 \text{ V}$	-	-	5	μΑ
I <sub>DSX</sub>	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	-	25	-	Α
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	300	nA
9fs	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 7.2 \text{ A}$	-	10	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 5 \text{ A}$	-	0.1	0.165	Ω

# 7. Application information

#### **Table 7.** Application information

Mode of operation: 2-carrier W-CDMA; PAR 7.5 dB at 0.01 % probability on CCDF; 3GPP test model 1; 1 to 64 PDPCH;  $f_1$  = 1802.5 MHz;  $f_2$  = 1807.5 MHz;  $f_3$  = 1872.5 MHz;  $f_4$  = 1877.5 MHz; RF performance at  $V_{DS}$  = 28 V;  $I_{Dq}$  = 2000 mA;  $T_{case}$  = 25 °C; unless otherwise specified; in a class-AB production test circuit

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$G_p$	power gain	$P_{L(AV)} = 50 \text{ W}$	<tbd></tbd>	16.5	<tbd></tbd>	dB
$RL_{in}$	input return loss	$P_{L(AV)} = 50 \text{ W}$	-	-10	<tbd></tbd>	dB
$\eta_{D}$	drain efficiency	$P_{L(AV)} = 50 \text{ W}$	<tbd></tbd>	29.5	-	%
ACPR	adjacent channel power ratio	$P_{L(AV)} = 50 \text{ W}$	-	-35	<tbd></tbd>	dBc

### Table 8. Application information

Mode of operation: 1-carrier W-CDMA; PAR 7.5 dB at 0.01 % probability on CCDF; 3GPP test model 1; 1 to 64 PDPCH;  $f_1$  = 1872.5 MHz;  $f_2$  = 1877.5 MHz; RF performance at  $V_{DS}$  = 28 V;  $I_{Dq}$  = 2000 mA;  $T_{case}$  = 25 °C; unless otherwise specified; in a class-AB production test circuit.

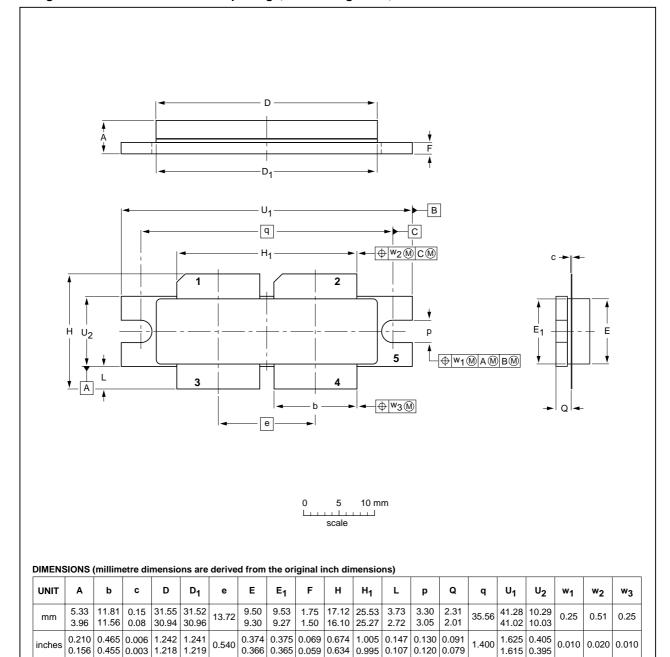
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
PARO	output peak-to-average ratio	P <sub>L(AV)</sub> = 115 W; at 0.01 % probability on CCDF	-	4.3	-	dB

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## 8. Package outline

### Flanged balanced LDMOST ceramic package; 2 mounting holes; 4 leads

SOT539A



OUTLINE		REFERENCES			EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT539A						<del>-99-12-28-</del> 00-03-03

Fig 1. Package outline SOT539A

### 9. Abbreviations

Table 9. Abbreviations

Acronym	Description
3GPP	Third Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
DPCH	Dedicated Physical CHannel
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
LDMOST	Laterally Diffused Metal-Oxide Semiconductor Transistor
PAR	Peak-to-Average power Ratio
PDPCH	transmission Power of the Dedicated Physical CHannel
RF	Radio Frequency
W-CDMA	Wideband Code Division Multiple Access

# 10. Revision history

### Table 10. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF6G20-230PRN_1	20081202	Objective data sheet	-	-

### 11. Legal information

#### 11.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
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